

Search Notes

Application No.

10/023,344

Examiner

Lao Y Lun

Applicant(s)

MIWA ET AL.

Art Unit

2673

SEARCHED

Class	Subclass	Date	Examiner
345	87-104		
	204-205	3/3/2006	LL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East Search		
esp@cenet		
IEEE XPLORE		
CIPO(Canadian Patent)	3/3/2006	LL